AMENDMENT AND PRESENTATION OF CLAIMS

Please replace all prior claims in the present application with the following claims.

1. (Currently Amended) A high-frequency measuring system for measuring a device under test, comprising:

a measuring-device unit; and

~~at least one~~ a first high-frequency module including a transmitter device configured to communicate with the device under test and a second high-frequency module including a receiver device configured to communicate with the device under test, wherein each high-frequency module is placed spatially separated from the measuring-device unit and each high-frequency module is connected to the measuring-device unit via a digital interface ~~for transmitting data to the at least one high-frequency module~~,

wherein ~~input data manually input into~~ the measuring-device unit is configured to process input data input into the measuring-device unit ~~processed in the measuring-unit device~~ to form a bitstream for transmission via the digital interface to the ~~at least one~~ first high-frequency module, and the first high-frequency module is configured to subsequently ~~forwarded~~ forward the bitstream to the device under test using the transmitter device, the processing of the input data including assigning symbols to states in a state diagram of an I-Q (in phase – quadrature phase) level in the measuring-device unit~~, and~~

~~wherein at least a first high-frequency module comprises a transmitter device and at least a second high-frequency module comprises a receiver device configured to communicate with the device under test~~.

2. (Canceled)

3. (Previously Presented) A high-frequency measuring system according to claim 1, wherein the digital interface is a serial interface.

4. (Previously Presented) A high-frequency measuring system according to claim 1, wherein the digital interface is a parallel interface.

5. (Previously Presented) A high-frequency measuring system according to claim 1, wherein the digital interface is an optical interface.

6. (Previously Presented) A high-frequency measuring system according to claim 1, wherein the digital interface is an electrical interface.

7. (Currently Amended) A high-frequency measuring system according to claim 1, wherein ~~the~~ at least one of the first and second high-frequency ~~module~~ modules is supplied with electrical energy via a power-supply unit independent from the measuring-device unit.

8. (Previously Presented) A high-frequency measuring system according to claim 1, wherein a plurality of identical ports are provided on the measuring-device unit for the digital interface.

9. (Previously Presented) A high-frequency measuring system according to claim 1, wherein a plurality of different ports are provided on the measuring-device unit for the digital interface.

10. (Currently Amended) A high-frequency measuring system according to claim 1, wherein control data or user data is transmitted in a standardized form via the digital interface, and wherein the ~~at least one~~ first high-frequency module comprises means for processing a high-frequency signal with regard to the transmission of data in standardized form via the digital interface or for processing the data transmitted in standardized form with regard to at least one predetermined transmission standard for the high-frequency signal.

11. (Previously Presented) A high-frequency measuring system according to claim 1, wherein the input data is manually input by any one of operating keys, a rotary knob, or arrow keys.

12. (Currently Amended) A high-frequency measuring system for measuring a device under test, comprising:

a measuring-device unit for receiving input data from a user; and

~~at least one~~ a first high-frequency module including a transmitter device configured to communicate with the device under test and a second high-frequency module including a receiver device configured to communicate with the device under test, wherein each high-frequency module is placed spatially separated from the measuring-device unit and each high-frequency module is connected to the measuring-device unit via a digital interface,

wherein the receiver device is configured to receive a message comprising a high-frequency signal originating from the device under test ~~is transmitted to the at least one high-frequency module~~, the second high-frequency module being configured to process the high-frequency signal ~~being processed by the at least one high-frequency module~~ to form a first bitstream for transmission via the digital interface to the measuring-device unit, the processing, by the ~~at least one~~ second high-frequency module, including converting the high-frequency signal to an intermediate-frequency signal and digitizing the intermediate-frequency signal for transmission via the digital interface to the measuring-device unit for evaluation of the message, and

wherein ~~the input data is processed in~~ the measuring-device unit is configured to process the input data to form a second bitstream for transmission via the digital interface to the ~~at least one~~ first high-frequency module, and the first high-frequency module is configured to subsequently ~~forwarded~~ forward the second bitstream to the device under test using the transmitter device~~, and~~

~~wherein at least a first high-frequency module comprises a transmitter device and at least a second high-frequency module comprises a receiver device configured to communicate with the device under test.~~

13. (Canceled)

14. (Previously Presented) A high-frequency measuring system according to claim 12, wherein the conversion of the high-frequency signal to an intermediate-frequency signal includes

receiving the high-frequency signal at the receiver device and subsequently mixing the high-frequency signal with a signal generated by a first local oscillator.

15. (Previously Presented) A high-frequency measuring system according to claim 14, wherein the intermediate-frequency signal is subdivided into an in-phase branch and a quadrature-phase branch and mixed in the in-phase branch with a signal generated by a second local oscillator.

16. (Currently Amended) A method for testing a device under test, comprising:

receiving input data from a user;

forming, based on the input data, a first bitstream for transmission via a digital interface to ~~at least one~~ a first high-frequency module, ~~and~~ the first high-frequency module including a transmitter configured to communicate with the device under test to subsequently ~~forwarded~~ forward the first bitstream to the device under test[[;]], wherein the first bitstream forming includes assigning symbols to states relating to an I-Q (in phase – quadrature phase) level; and

receiving a second bitstream representative of high-frequency signal messages originating from the device under test via ~~the at least one~~ a second high-frequency module including a receiver configured to communicate with the device under test, the ~~at least one~~ second high-frequency module processing the high-frequency signal messages to form the second bitstream, the processing, by the ~~at least one~~ second high-frequency module, including converting the high-frequency signal messages to intermediate-frequency signals and digitizing the intermediate-frequency signals~~, and~~

~~wherein at least a first high-frequency module comprises a transmitter device and at least a second high-frequency module comprises a receiver device configured to communicate with the device~~.

17. (Previously Presented) A method according to claim 16, further comprising:

determining a specific bit sequence to be transmitted to the device under test.

18. (Currently Amended) A method according to claim 17, further comprising:

generating one or more control signals in the bit sequence to control the ~~at least one~~ first high-frequency module.

19. (Previously Presented) A method according to claim 16, wherein the input data is input by the user using any one of operating keys, a rotary knob, or arrow keys.

20. (Canceled)